

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/588,480	YOON ET AL.	
Examiner		Art Unit		Page 1 of 1
QUN SHEN		2617		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0142698 A1	07-2004	Pietraski, Philip J.	455/452.2
*	B	US-2004/0179493 A1	09-2004	Khan, Farooq Ullah	370/332
*	C	US-2005/0143084 A1	06-2005	Cheng et al.	455/452.2
*	D	US-2005/0260998 A1	11-2005	Casaccia et al.	455/452.2
*	E	US-2005/0289256 A1	12-2005	Cudak et al.	710/062
*	F	US-2008/0287138 A1	11-2008	Yoon et al.	455/452.2
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.